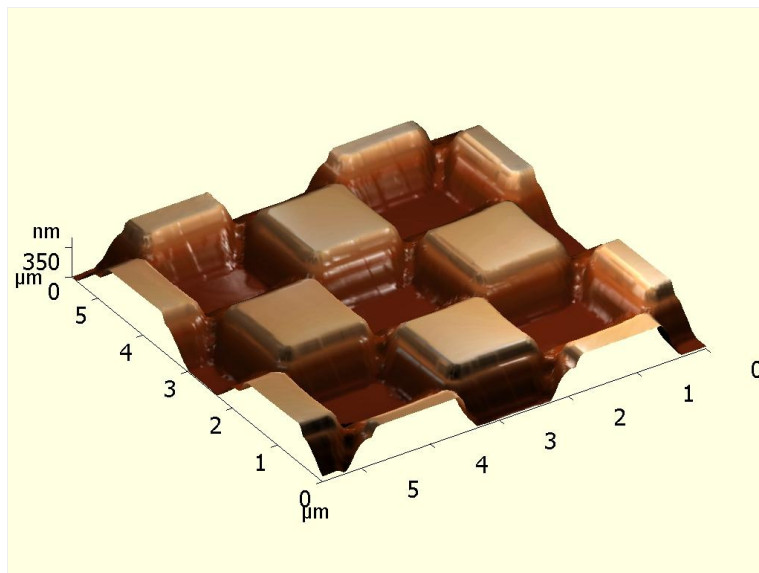
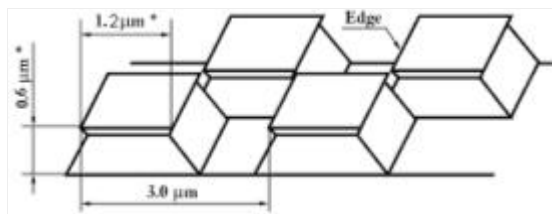


Product Description

Calibration grating TGX1 is intended for

- lateral calibration of AFM scanners
- detection of lateral non-linearity, hysteresis, creep, and cross-coupling effects;
- determination of the tip sharpness.



AFM image of TGX1

grating.

General Features

Structure	Si
Pattern type	chessboard-like array of square pillars with sharp undercut edges
Period	$3\pm 0,05\ \mu\text{m}$
Height	$\sim 0,6\ \mu\text{m}$
Chip size	$5\times 5\times 0,5\ \text{mm}$
Effective area	central square $3\times 3\ \text{mm}$
Edge curvature radius	less than 10nm

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